- BiCMOS Design Significantly Reduces I<sub>CCZ</sub>
- 3-State True Outputs Drive Bus Lines Directly
- High-Impedance State During Power Up and Power Down
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015
- Package Options Include Plastic Small-Outline (DW) Packages and Standard Plastic 300-mil DIPs (N)

#### DIR 19 OE A1 2 18 B1 А2 П 3 А3 [ 4 17 B2 **B**3 5 A4 📙 16 А5 П 15 ∏ B4 6 A6 [ ∏ B5 A7 🛮 8 13 B6 A8 🛮 9 12 B7 **∏** B8 GND [ 10

DW OR N PACKAGE (TOP VIEW)

### description

This octal bus transceiver is designed for asynchronous communication between data

buses. The devices transmit data from the A bus to the B bus or from the B bus to the A bus depending upon the logic level at the direction-control (DIR) input. The output-enable  $(\overline{OE})$  input can be used to disable the device so the buses are effectively isolated.

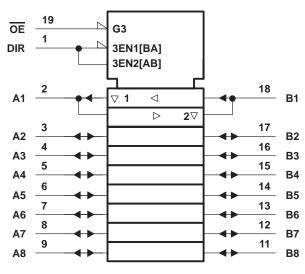
The outputs are in a high-impedance state during power up and power down while the supply voltage is less than approximately 3 V.

The SN64BCT245 is characterized for operation from −40°C to 85°C and 0°C to 70°C.

#### **FUNCTION TABLE**

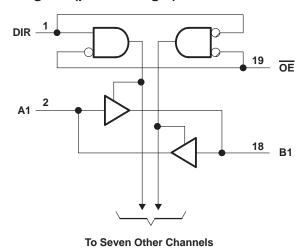
INP	UTS	OPERATION					
OE	DIR	OPERATION					
L	L	B data to A bus					
L	Н	A data to B bus					
н	X	Isolation					

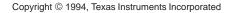
## logic symbol†



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

# logic diagram (positive logic)





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# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	– 0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	– 0.5 V to 7 V
Voltage range applied to any output in the disabled or power-off state, V <sub>O</sub>	0.5 V to 5.5 V
Voltage range applied to any output in the high state, V <sub>O</sub>	$\dots$ – 0.5 V to V <sub>CC</sub>
Current into any output in the low state	128 mA
Operating free-air temperature range	− 40°C to 85°C
Storage temperature range	. − 65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### recommended operating conditions

				NOM	MAX	UNIT
Vcc	Supply voltage				5.5	V
VIH	V <sub>IH</sub> High-level input voltage					V
$V_{IL}$	/IL Low-level input voltage				0.8	V
liK	Input clamp current				-18	mA
1	High-level output current	A1-A8			-3	mA
IOH Hig	ngri-level output current	B1-B8			-15	111/4
IOL Lo	Low lovel output ourropt	A1-A8	24		mA	
	Low-level output current	B1-B8			64	IIIA
TA	Operating free-air temperature				85	°C

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP <sup>†</sup>	MAX	UNIT
VIK		V <sub>CC</sub> = 4.5 V,	I <sub>I</sub> = -18 mA				-1.2	V
	Any A		I <sub>OH</sub> = -1 mA		2.5	3.4		
Vон	Any A or B	V <sub>CC</sub> = 4.5 V	$I_{OH} = -3 \text{ mA}$		2.4	3.3		V
Any B			I <sub>OH</sub> = -15 mA					
V	Any A	V 45V	I <sub>OL</sub> = 24 mA			0.35	0.5	V
VOL	Any B	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 64 mA		0.42	0.55	V	
	Power up	Va a 0 to 2 2 V	V <sub>O</sub> = 2.7 V	<u></u>			70	μΑ
	Power up	$V_{CC} = 0$ to 2.3 V	V <sub>O</sub> = 0.5 V	OE at 0.8 V			-0.65	mA
loz	Dawen dawe	V 4.0.V+c.0	V <sub>O</sub> = 2.7 V	<u></u>			70	μΑ
	Power down	$V_{CC} = 1.8 \text{ V to } 0$	V <sub>O</sub> = 0.5 V	OE at 0.8 V			-0.65	mA
. +	A and B	\/ 55\/	V <sub>I</sub> = 5.5 V				1	mA
1 ‡	DIR and OE	V <sub>CC</sub> = 5.5 V,					0.1	mA
. +	A and B	Vac 55V	V. 27V				70	
¹ <sub>IH</sub> ‡	DIR and OE	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V				20	μΑ
	A and B	V 55V	V: 05V				-0.65	m^
IIL.	DIR and OE	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.5 V				-1.2	mA
	s Any A	V 55V	V <sub>O</sub> = 0		-60		-150	mA
los§	Any B	V <sub>CC</sub> = 5.5 V,			-100		-225	
ICCH	A-to-B	V <sub>CC</sub> = 5.5 V				36	57	
ICCL	A-to-B	V <sub>CC</sub> = 5.5 V				57	90	mA
I <sub>CCZ</sub>		V <sub>CC</sub> = 5.5 V				10	15	
Ci	OE and DIR	V <sub>CC</sub> = 5 V,	V <sub>I</sub> = 2.5 V or 0.5 V			7		pF
C.	A to B	\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	V <sub>I</sub> = 2.5 V or 0.5 V			9		n.E
C <sub>io</sub>	B to A	V <sub>CC</sub> = 5 V,				12		pF

# switching characteristics (see Note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = C <sub>L</sub> = 5 R1 = 5 R2 = 5 T <sub>A</sub> = 2	50 pF, 500 Ω, 500 Ω,	C <sub>L</sub> R1	= 50 pF, = 500 Ω, = 500 Ω	,	0°C	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
<sup>t</sup> PLH	A or B	A or B	1	6	1	7.2	1	7	
t <sub>PHL</sub>		B or A	1.5	6.6	1.5	7.6	1.5	7	ns
<sup>t</sup> PZH	ŌĒ	A or B	1.5	9.4	1.5	11.2	1.5	10.9	ns
t <sub>PZL</sub>			1.5	10.2	1.5	11.8	1.5	11.6	115
<sup>t</sup> PHZ	ŌĒ	A or B	1.5	8.3	1.5	9.7	1.5	9.3	ns
<sup>t</sup> PLZ		AUID	1.5	7.8	1.5	9.6	1.5	9.1	115

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



<sup>†</sup> All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C. ‡ For I/O ports, the parameters I<sub>IH</sub> and I<sub>IL</sub> include the off-state output current. § Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

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